Features

- High Performance Programmable Logic Device 7.5 ns Max Propagation Delay Up to 166 MHz Operation 5 V ± 10% Operation
- Fully Compatible with Standard 22V10 Identical Functionality/Fuse-Map
- TTL Compatible Inputs and Outputs 10 μA Leakage Maximum
- Reprogrammable Tested 100% for Programmability
- High Reliability Proven UV Erasable CMOS Technology 2000 V ESD Protection 200 mA Latch-Up Protection
- Full Military, Commercial and Industrial Temperature Ranges
- Dual-In-Line and Surface Mount Packages with Standard Pinouts

OE PRODUCT TERMS PROGRAMMABLE 12 INTERCONNECT LOGIC 10 OUTPUT INPUT PINS AND OPTION I/O PINS OPTION COMBINATORIAL 8 TO 16 LOGIC ARRAY (UP T0 10 PRODUCT FLIP-FLOPS) TERMS

High Speed UV Erasable Programmable Logic Device

Description

Logic Diagram

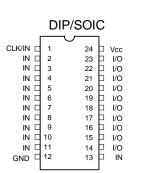
The AT22V10B is an ultra-high performance CMOS Programmable Logic Device (PLD). Speeds down to 7.5 ns and operation up to 166 MHz are offered. All pins offer a low \pm 10 μ A leakage.

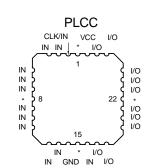
The AT22V10B logic functionality is fully compatible with the standard 22V10. The 12 dedicated inputs and ten configurable I/O pins allow implementation of logic requiring up to 22 input signals. The AT22V10B also provides individual output enable product terms for each of the ten I/Os.

(continued)

Pin Configurations

Pin Name	Function
CLK/IN	Clock and Logic Input
IN	Logic Inputs
I/O	Bidirectional Buffers
*	No Internal Connection
VCC	+5 V Supply



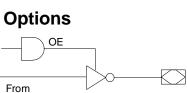






1-110

Output Options OE

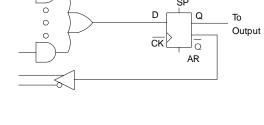


То

Output

From Output

I/O



 \geq

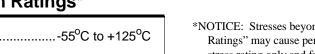
I/O

OE

From

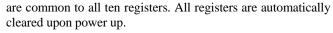
Logic

Option



Temperature Under Bias55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground
Voltage on Input Pins with Respect to Ground During Programming2.0 V to +14.0 V ⁽¹⁾
Programming Voltage with Respect to Ground2.0 V to +14.0 $V^{(1)}$
Integrated UV Erase Dose

Absolute Maximum Ratings*



Register preload simplifies testing. A security fuse prevents unauthorized copying of programmed fuse patterns.

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note:

1. Minimum voltage is -0.6 V dc which may undershoot to -2.0 V for pulses of less than 20 ns. Maximum output pin voltage is V_{CC}+0.75 V dc which may overshoot to +7.0 V for pulses of less than 20 ns.

Description (Continued)

The AT22V10B incorporates a variable product term architecture. Each output is allocated from eight to 16 product terms, which allows highly complex logic functions to be realized.

The AT22V10B includes two additional product terms to provide synchronous preset and asynchronous reset. These terms

Logic Options

0

0

0

Logic

Option



D.C. and A.C. Operating Conditions

	Commercial AT22V10B -7	Commercial AT22V10B -10	Industrial AT22V10B -10	Military AT22V10B -10
Operating Temperature (Case)	0°C - 70°C	0°C - 70°C	-40°C - 85°C	-55°C - 125°C
V _{CC} Power Supply	$5 \text{ V} \pm 5\%$	$5~V\pm10\%$	$5~V\pm10\%$	$5~V\pm10\%$

D.C. Characteristics

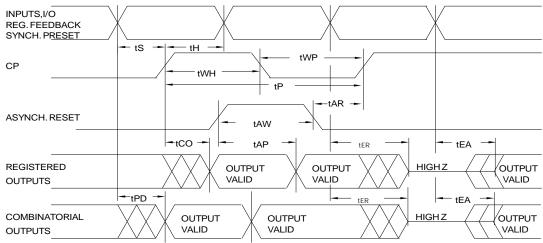
Symbol	Parameter	Condition			Min	Max	Units
ILI	Input Load Current	$V_{IN} = -0.1 V$ to V_{CC}	+1 V			10	μA
Ilo	Output Leakage Current	$V_{OUT} = -0.1 V \text{ to } V_{OUT}$	c+0.1 V			10	μA
	Dower Supply Current	$f = 0$ MHz to F_{MAX} , $V_{CC} = MAX$, Com.			140	mA	
lcc	Power Supply Current	V _{IN} = GND, Outputs Open Ind., Mil.				160	mA
los (1)	Output Short Circuit Current	V _{OUT} = 0.5 V			-30	-120	mA
VIL	Input Low Voltage				-0.6	0.8	V
Vih	Input High Voltage				2.0	V _{CC} +0.75	V
		., ., .,	IoL = 16 mA	Com.,Ind.		0.5	V
Vol	Output Low Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL},$ $V_{CC} = MIN$ $I_{OL} = 12 \text{ mA}$ Mil.	Mil.		0.5	V	
			I _{OL} = 24 mA	Com.		0.8	V
Vон	Output High Voltage	V _{IN} = V _{IH} or V _{IL} , V _{CC} = MIN	I _{OH} = -4.0 mA		2.4		V

Notes: 1. Not more than one output at a time should be shorted. Duration of short circuit test should not exceed 30 sec.





A.C. Waveforms⁽¹⁾



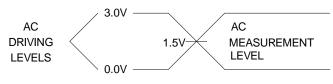
Note: 1. Timing measurement reference is 1.5 V. Input AC driving levels are 0.0 V and 3.0 V, unless otherwise specified.

A.C. Characteristics

		AT22V10B-7		AT22V10B-10				
Symbol	Parameter	Min	Тур	Max	Min	Тур	Max	Units
tPD	Input or Feedback to Non-Registered Output		5	7.5		6	10	ns
t _{EA}	Input to Output Enable		5	7.5		6	10	ns
tER	Input to Output Disable		5	7.5		6	10	ns
tcr ⁽¹⁾	Clock to Feedback	0	1	2	0	1	2	ns
tco	Clock to Output	0	3.5	5.5	0	4	7	ns
ts	Input or Feedback Setup Time	3.5	2		5	3		ns
tн	Hold Time	0			0			ns
tP	Clock Period	6			7			ns
twL ⁽¹⁾	Clock Width Low	3			3.5			ns
twn	Clock Width High	3			3.5			ns
	External Feedback 1/(t _S +t _{CO})			111			83	MHz
FMAX	Internal Feedback 1/(ts + tcF)			166			142	MHz
	No Feedback 1/(tp)			166			142	MHz
taw	Asynchronous Reset Width	6	3		7	4		ns
t _{AR}	Asynchronous Reset, Synchronous Preset, Recovery Time	7	4		8	5		ns
tap	Asynchronous Reset to Registered Output Reset		6	10		8	14	ns

Note: 1. This parameter is only sampled and is not 100% tested.

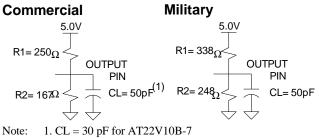
Input Test Waveforms and Measurement Levels



AT22V10B

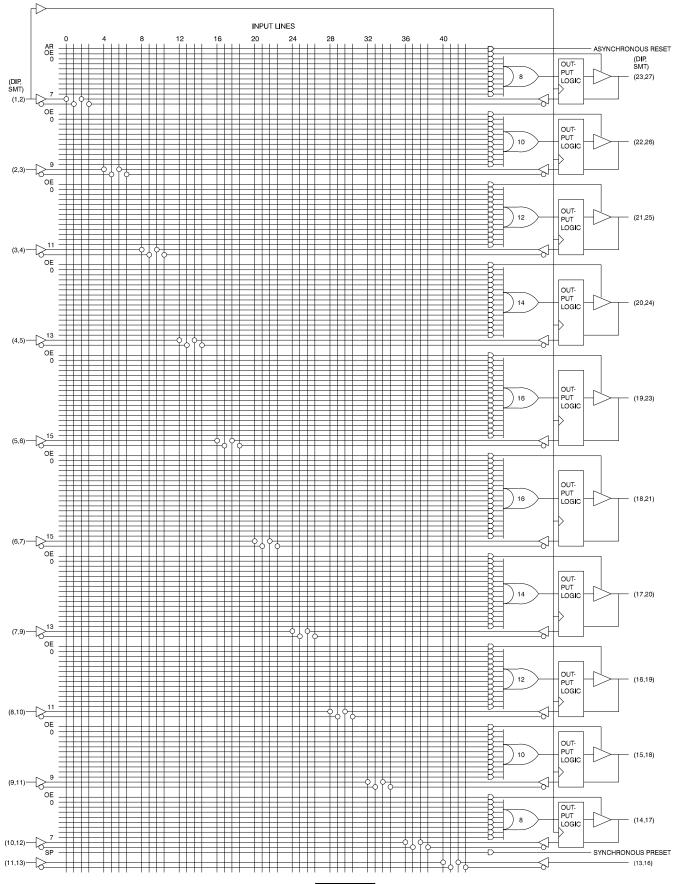
tR, tF $< 2 \ ns$ $\$ (10% to 90%)

Output Test Loads:



AT22V10B

Functional Logic Diagram AT22V10B



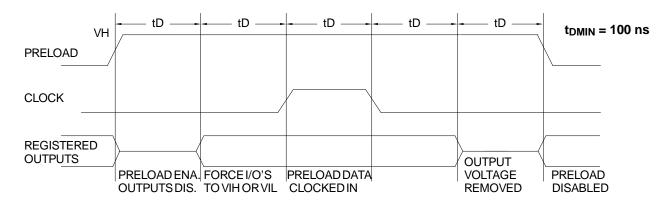




Preload of Registered Outputs

The registers in the AT22V10B are provided with circuitry to allow loading of each register asynchronously with either a high or a low. This feature will simplify testing since any state can be forced into the registers to control test sequencing. A V_{IH} level on the I/O pin will force the register high; a V_{IL} will force it low, independent of the polarity bit (C0) setting. The preload state is entered by placing an 10.5-V to 12-V signal on pin 8 on DIPs, and pin 10 on SMPs. When the clock pin is pulsed high, the data on the I/O pins is placed into the ten registers.

Level forced on registered output pin during preload cycle	Register state after cycle			
VIH	High			
VIL	Low			



Power Up Reset

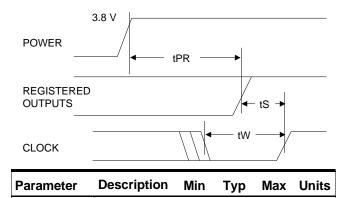
The registers in the AT22V10B are designed to reset during power up. At a point delayed slightly from V_{CC} crossing 3.8 V, all registers will be reset to the low state. The output state will depend on the polarity of the output buffer.

This feature is critical for state machine initialization. However, due to the asynchronous nature of reset and the uncertainty of how V_{CC} actually rises in the system, the following conditions are required:

1) The V_{CC} rise must be monotonic,

2) After reset occurs, all input and feedback setup times must be met before driving the clock pin high, and

3) The clock must remain stable during tPR.



1000

ns

600

Power-Up

Reset Time

Pin Capacitance $(f = 1 \text{ MHz}, T = 25^{\circ}\text{C})^{(1)}$

	Тур	Max	Units	Conditions
C _{IN}	5	8	pF	$V_{IN} = 0 V$
Соит	6	8	pF	V _{OUT} = 0 V

tPR

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

Erasure Characteristics

The entire fuse array of an AT22V10B is erased after exposure to ultraviolet light at a wavelength of 2537 Å. Complete erasure is assured after a minimum of 20 minutes exposure using 12,000 μ W/cm² intensity lamps spaced one inch away from the chip. Minimum erase time for lamps at other intensity ratings can be

AT22V10B

calculated from the minimum integrated erasure dose of 15 W-sec/cm². To prevent unintentional erasure, an opaque label is recommended to cover the clear window on any UV erasable PLD which will be subjected to continuous fluorescent indoor lighting or sunlight.

AT22V10B

